

Field Emission Scanning Electron Microscope (FE-SEM)

Manufacturer: Carl Zeiss

Model: Supra 55

Description

SUPRA 55 FE-SEM is a general purpose ultra high resolution FE-SEM based on the unique GEMINI Technology. It provided excellent imaging properties combined with analytical capabilities which make this high end FE-SEM suitable for a wide range of applications in materials science, life science and semiconductor technology. The large specimen chamber for the integration of optional detectors and accessories enables the user to configure the SUPRA for specific applications without sacrificing productivity or efficiency.

Specifications and Key Advantages

- GEMINI Technology with high efficiency in-lens detector and no magnetic field at specimen level
- Super resolution (up to 1nm) and image quality at high and low operating voltages
- Extremely wide operating voltage range from 0.02-30kV
- Designed-in ease of use with minimal adjustments required when changing operating conditions
- Short analytical working distance of 8.5 mm for simultaneous high resolution imaging and X-ray analysis
- High probe current (up to 100 nA) with high stability (better than 0.2%/h) for precise analytical results
- Multi-User friendly with Windows® based SmartSEM control software.

Operation procedures and instruction manual can be obtained from person in charge.

Note: booking system is available for FE-SEM via *Quartz*. Please approach person in charge for more details.

